

<b>Notice of References Cited</b>	Application/Control No. 10/600,377	Applicant(s)/Patent Under Reexamination HOU ET AL.	
	Examiner Duy-Vu N. Deo	Art Unit 1765	Page 1 of 1

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*	A	US-6,207,565	03-2001	Yeh et al.	438/669
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	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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